

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination NISHI ET AL.	
		Examiner BRIAN P. YENKE	Art Unit 2622	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Frankowski, "Real-time 3D Shape Measurement with Digital Strip Projection by Texas Instruments Micromirror Devices DMD", SPE Vol 3958 (2000), pp 90-105.
	V	
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	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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